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Examiner-GAU	Fred - 228	Date	10-29-04
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| a. Serial No. | f. Foreign Priority | k. Print Claim(s) | (p) PTO-1449 |
| b. Applicant(s) | g. Disclaimer | l. Print Fig. | q. PTOL-85b |
| c. Continuing Data | h. Microfiche Appendix | m. Searched Column | r. Abstract |
| d. PCT | i. Title | n. PTO-270/328 | s. Sheets/Figs |
| e. Domestic Priority | j. Claims Allowed | o. PTO-892 | t. Other |

SPECIFICATION

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- b. Text Continuity
- c. Holes through Data
- d. Other Missing Text
- e. Illegible Text
- f. Duplicate Text
- g. Brief Description
- h. Sequence Listing
- i. Appendix
- j. Amendments
- k. Other

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Citations dated 10-10-03. Copy provided
for reference. (25 pages)

CLAIMS

- a. Claim(s) Missing
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RESPONSE

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U.S. Department of Commerce, Patent and Trademark Office				Atty.Docket No.	Serial No.		
				01N006-1C US	09/849,005		
INFORMATION DISCLOSURE STATEMENT BY APPLICANT <i>(Use several sheets if necessary)</i>				Applicants: Chian-Min Ho et al.			
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				MAY 4, 2001	2123		
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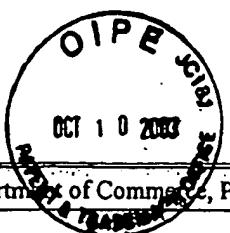
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PART "B"
Sheet 8 of 24

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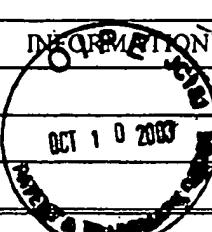
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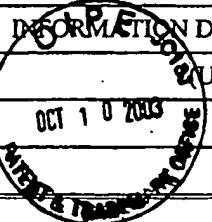
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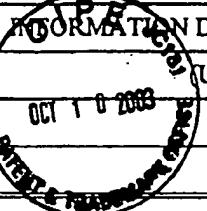
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	AI	Seawright, A., et al., "A System for Compiling and Debugging Structured Data Processing Controllers", EURO, Design Automation Conference, 1996.
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U.S. Patent Documents								
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	AA							
	AB							
	AC							
	AD							
	AE							
	AF							
Foreign Patent Documents							Translation	
		Document	Date	Country	Class	Subclass	Yes	No
	AG							
	AH							
OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)								
	AI	Singer, S., et al., "Next Generation Test Generator (NGTG) for Digital Circuits", AUTOTESTCON, 97. 1997 IEEE Autotestcon Proceedings, Septe. 22-25, 1997, pp. 105-112.						
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